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Lucent Technologies
Bell Labs Innovations

TRCV012G5 (2.5 Gbits/s) and TRCV012G7 (2.5 Gbits/s and 2.7 Gbits/s) Limiting Amplifier, Clock Recovery, 1:16 Data Demultiplexer

Features

- TRCV012G5 supports OC-48/STM-16 data rate
- TRCV012G7 supports:
  — OC-48/STM-16 data rate
  — RS (255, 239) forward error correction (FEC) OC-48/STM-16 data rate
- Fully-integrated limiting amplifier, clock recovery, 1:16 data demultiplexer
- No reference clock required for CDR
- 2.5 Gbits/s data output and 2.5 GHz recovered clock output available for wavelength division multiplex (WDM) or regenerator applications
- Programmable limiting amplifier offset
- Programmable data sampling phase
- Additional CML serial data input for system loopback
- Parity bit generation
- Analog and digital loss of signal (LOS) indicators
- Optional demultiplexer powerdown mode conserves power
- Single 3.3 V supply
- Available in either MBIC 025 BiCMOS technology or lower-power MBIC 025 silicon germanium BiCMOS technology
- High-speed LVPECL digital I/O
- Jitter tolerance, transfer, and generation compliant with the following:
  — *Telcordia Technologies** GR-253
  — ITU-T G.825
  — ITU-T G.958
- Loss of signal compliant with the following:
  — *Telcordia Technologies* GR-253

* *Telcordia Technologies* is a registered trademark of Bell Communications Research, Inc.

Applications

- SONET/SDH line termination equipment
- SONET/SDH add/drop multiplexers
- SONET/SDH cross connects
- SONET/SDH test equipment

Description

The Lucent Technologies Microelectronics Group TRCV012G5 operates at the OC-48/STM-16 data rate of 2.5 Gbits/s. The TRCV012G7 device operates at either 2.5 Gbits/s or the RS FEC OC-48/STM-16 data rate of 2.7 Gbits/s. For clarity, this data sheet refers to the TRCV012G5 serial data rate as 2.5 Gbits/s and the parallel data and reference clock frequency as 155 MHz. (The precise rates are 2.48832 Gbits/s and 155.52 MHz.) When using the TRCV012G7 at the FEC rate, the 2.5 Gbits/s data rate should be interpreted as 2.7 Gbits/s and the parallel and clock frequency should be interpreted as 166 MHz. (The precise rates are 2.66606 Gbits/s and 166.62 MHz.)

The devices contain a limiting amplifier with 30 dB gain, a clock and data recovery PLL with high-speed serial clock and data outputs, and a 1:16 demultiplexer with differential PECL data and clock outputs.

The device provides improved optical receiver performance when used in optically amplified systems due to a direct slice adjust input pin and a 6 ps adjustment capability in the slicing decision time. Both devices are available in either BiCMOS or in SiGe BiCMOS technology for lower power operation.

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Additional features include a user-programmable threshold for generating analog loss of signal (LOS) alarms, a digital LOS transition detector, an optional reference clock input that can maintain synchronization with no data input signal present, and a loopback data input. To reduce power consumption, the demultiplexer unit, high-speed serial recovered data and clock output, low-speed clock, and low-speed demultiplexer clock output can be independently powered down in applications where they are not required.

The device may be used with the TTRN012G5 or TTRN012G7 transmit synthesizer and multiplexer.

Figure 1. Functional Block Diagram
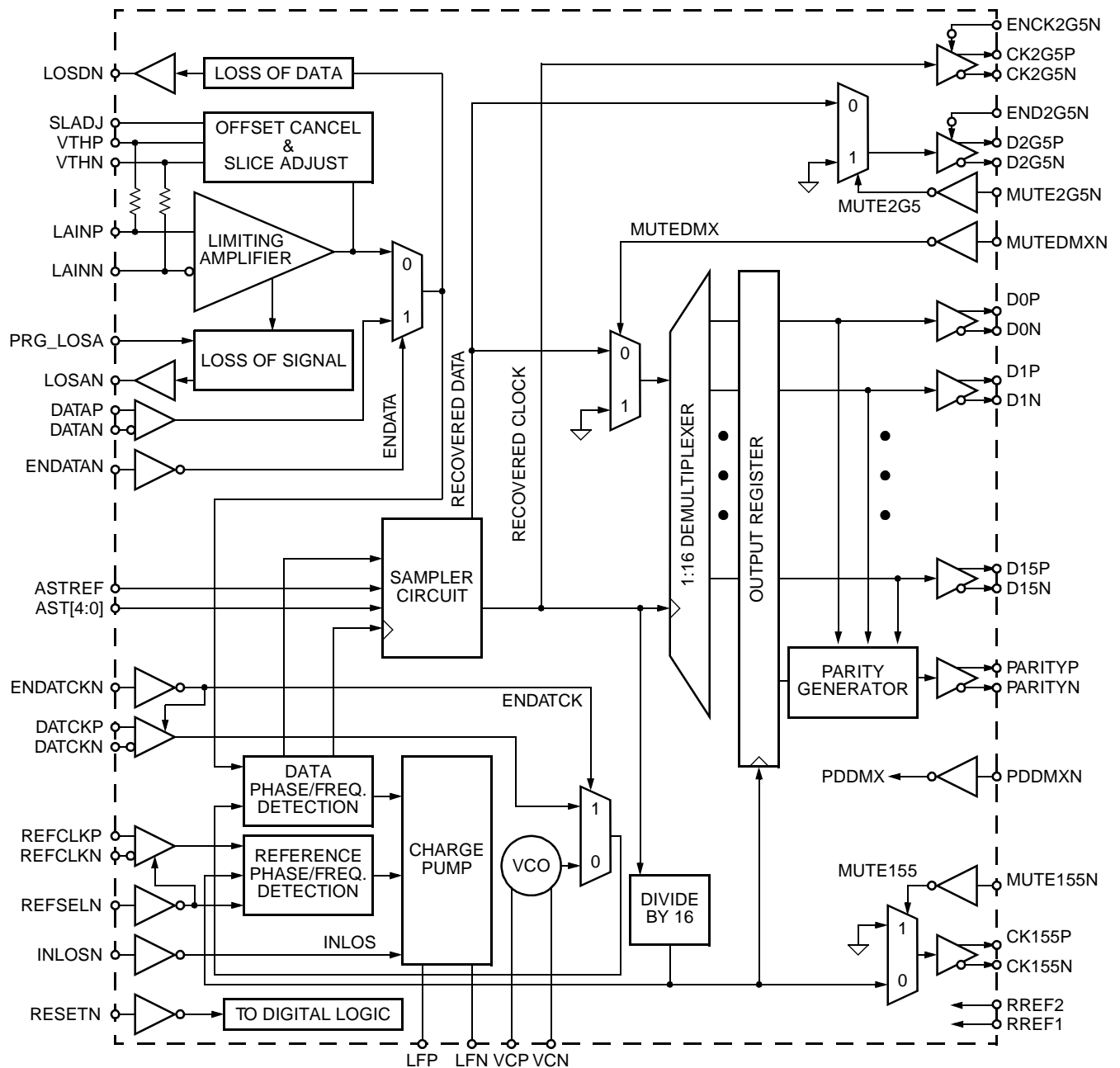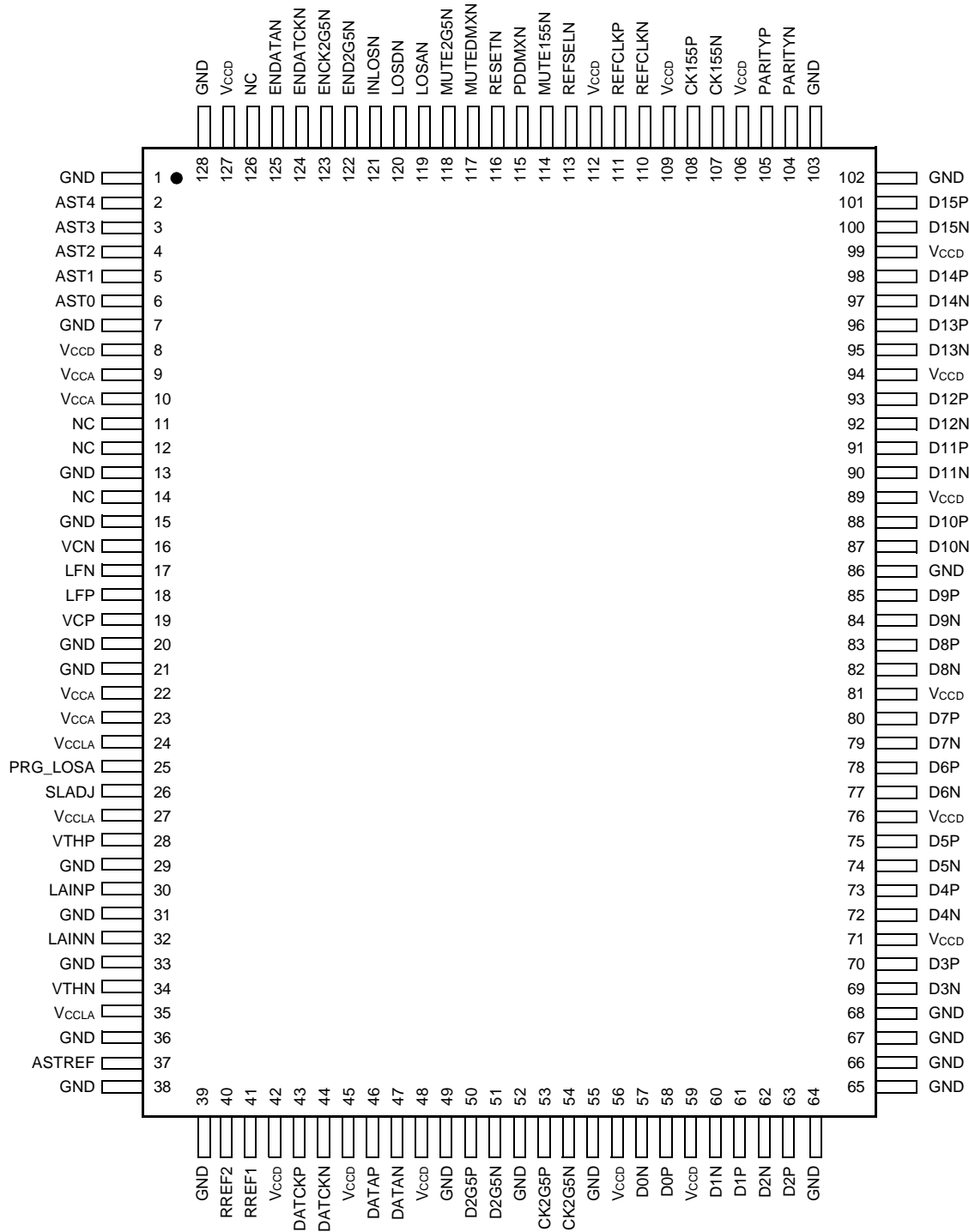
Note: Diagram is representative of device functionality and conceptual signal flow. Internal implementation details may be different than shown.

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Pin Information

Figure 2. Pin Diagram of 128-Pin QFP (Top View)

5-8071(F)r.5

Pin Information (continued)

Note: In Table 1, when operating the TRCV012G7 device at the OC-48/STM-16 rate, 2.5 Gbits/s should be interpreted as 2.48832 Gbits/s. When operating the TRCV012G7 device at the RS FEC OC-48/STM-16 rate, 2.5 Gbits/s should be interpreted as 2.66606 Gbits/s. (A similar interpretation should be made for 2.5 GHz.)

Table 1. Pin Descriptions—2.5 Gbits/s and Related Signals

Pin	Symbol*	Type†	Level	Name/Description
30	LAINP	I	Analog	**Limiting Amplifier Inputs (2.5 Gbits/s).**
32	LAINN			ac coupling required.
50	D2G5P	O	CML	**Data Output (2.5 Gbits/s NRZ).** 2.5 Gbits/s differential data output.
51	D2G5N			■ Pins are high impedance when END2G5N = 1. ■ Pins are active but forced to differential logic low when MUTE2G5N = 0.
122	END2G5N	Iᵘ	CMOS	**Enable D2G5P/N Data Outputs (Active-Low).** 0 = D2G5P/N buffer enabled 1 or no connection = D2G5P/N buffer powered off
118	MUTE2G5N	Iᵘ	CMOS	**Mute D2G5P/N Data Output (Active-Low).** 0 = muted 1 or no connection = normal data
53	CK2G5P	O	CML	**Recovered Clock Output (2.5 GHz).** 2.5 GHz recovered differential clock output. Pins are high impedance when ENCK2G5N = 1.
54	CK2G5N			
123	ENCK2G5N	Iᵘ	CMOS	**Enable CK2G5P/N Clock Output (Active-Low).** 0 = CK2G5P/N buffer enabled 1 or no connection = CK2G5P/N buffer powered off
41	RREF1	I	Analog	**Resistor Reference 1.** CML current bias reference resistor. (See Table 16, page 22 for values.)
40	RREF2	I	Analog	**Resistor Reference 2.** CML bias reference resistor. Place a 1.5 kΩ resistor to V_{CCD}.
28	VTHP	I	Analog	**Voltage Threshold Adjust Input.** This input is for monitoring purposes only and should be left open (see Figure 3 on page 10).
34	VTHN			
26	SLADJ	I	Analog	**Slice Level Adjustment.** Adjusts slice level for the limiting amp (see Figure 3 on page 10).
119	LOSAN	O	Open Drain	**Loss of Analog Signal (Active-Low).**
25	PRG_LOSA	I	Analog	**Programming Voltage for LOSA Threshold.** Programming voltage is scaled (see Figure 7 on page 16).
120	LOSDN	O	Open Drain	**Loss of Digital Data (Active-Low).**
121	INLOSN	Iᵘ	CMOS	**Input Loss of Signal (Active-Low).** Forces VCO to decrease to its minimum frequency. 0 = force VCO low 1 or no connection = normal operation
18	LFP	O	Analog	**Loop Filter PLL.** Connect LFP to VCP, and LFN to VCN.
17	LFN			
19	VCP	I	Analog	**VCO Control.** Connect VCP to LFP, and VCN to LFN.
16	VCN			

* Differential pins are indicated by the P and N suffixes. For nondifferential pins, N at the end of the symbol name designates active-low.
† I = input, O = output. Iᵘ = an internal pull-up resistor on this pin, Iᵈ = an internal pull-down resistor on this pin, Iᵗ = an internal termination resistance of 50 Ω on this pin.

Pin Information (continued)

Table 1. Pin Descriptions—2.5 Gbits/s and Related Signals (continued)

Pin	Symbol*	Type†	Level	Name/Description
43	DATCKP	I^t	CML	**Clock Input for DATAP/N.** Buffer is powered down when ENDATCKN = 1.
44	DATCKN			
124	ENDATCKN	I^u	CMOS	**External DATCKP/N Clock Select (Active-Low).** Selects external DATCKP/N clock to demultiplexer. 0 = select DATCKP/N 1 or no connection = select VCO clock
46	DATAP	I^t	CML	**Data Input for CML.** Use this input for system loopback data when LAINP/N is used.
47	DATAN			
125	ENDATAN	I^u	CMOS	**Enable DATAP/N Inputs (Active-Low).** Selects DATAP/N as data source rather than limiting amplifier output. 0 = select DATAP/N 1 or no connection = select LAINP/N
37	ASTREF	I	Analog	**Adjustable Sampling Circuit Reference Resistor.** Connect a 2.1 kΩ resistor to V$_{CCA}$.
2	AST4	I^d	CMOS	**Adjustable Sampling Time Control Inputs.** AST[4:0] allows introduction of an offset into the sampling time. The most significant bit (A4) is the sign bit and bits A[3:0] represent the magnitude. (See the Decision Circuit—Adjustable Sampling Time (ASTREF, AST[4:0]) section, page 15.) A4 is the polarity bit as follows: 1 = advance 0 = delay sampling point AST[3:0] provides adjustments in steps (increments or decrements) of 6.25 ps in the sampling instant.
3	AST3			
4	AST2			
5	AST1			
6	AST0			

* Differential pins are indicated by the P and N suffixes. For nondifferential pins, N at the end of the symbol name designates active-low.

† I = input, O = output. I^u = an internal pull-up resistor on this pin, I^d = an internal pull-down resistor on this pin, I^t = an internal termination resistance of 50 Ω on this pin.

Pin Information (continued)

Note: In Table 2, when operating the TRCV012G7 device at the OC-48/STM-16 rate, 155 Mbits/s should be interpreted as 155.52 Mbits/s. When operating the TRCV012G7 device at the RS FEC OC-48/STM-16 rate, 155 Mbits/s should be interpreted as 166.62 Mbits/s. (A similar interpretation should be made for 155 MHz.)

Table 2. Pin Descriptions—155.52 Mbits/s and Related Signals

Pin	Symbol*	Type†	Level	Name/Description
101	D15P	O	LVPECL	**Data Output (155 Mbits/s).** 155 Mbits/s differential data output. D15 is the most significant bit and is the first received on the LAINP/N or DATAP/N input.
100	D15N			
98	D14P		LVPECL	When PDDMXN = 0, data outputs can be left floating to reduce power consumption.
97	D14N			
96	D13P		LVPECL	
95	D13N			
93	D12P		LVPECL	
92	D12N			
91	D11P		LVPECL	
90	D11N			
88	D10P		LVPECL	
87	D10N			
85	D9P		LVPECL	
84	D9N			
83	D8P		LVPECL	
82	D8N			
80	D7P		LVPECL	
79	D7N			
78	D6P		LVPECL	
77	D6N			
75	D5P		LVPECL	
74	D5N			
73	D4P		LVPECL	
72	D4N			
70	D3P		LVPECL	
69	D3N			
63	D2P		LVPECL	
62	D2N			
61	D1P		LVPECL	
60	D1N			
58	D0P		LVPECL	
57	D0N			

* Differential pins are indicated by the P and N suffixes. For nondifferential pins, N at the end of the symbol name designates active-low.
† I = input, O = output. I^u = an internal pull-up resistor on this pin, I^d = an internal pull-down resistor on this pin, I^t = an internal termination resistance of 50 Ω on this pin.

Pin Information (continued)

Table 2. Pin Descriptions—155.52 Mbits/s and Related Signals (continued)

Pin	Symbol*	Type†	Level	Name/Description
115	PDDMXN	I^u	CMOS	**Powerdown Demultiplexer Circuit (Active-Low).** 0 = demultiplexer powered off, D[15:0]P/N and PARITYP/N are high-impedance 1 or no connection = demultiplexer powered on
117	MUTEDMXN	I^u	CMOS	**Mute Data to Demultiplexer Circuit (Active-Low).** 0 = mute data 1 or no connection = normal data
108	CK155P	O	LVPECL	**Recovered Clock Output (155 MHz).** 155 MHz recovered differential clock output. Pins are active but forced to differential logic low when MUTE155N = 0.
107	CK155N			
114	MUTE155N	I^u	CMOS	**Mute CK155P/N Clock Output (Active-Low).** Forces CK155P/N to logic low when MUTE155N is active. 0 = muted 1 or no connection = enabled
105	PARITYP	O	LVPECL	**Parity Input Over Data (D[15:0]).** Active only when PDDMXN = 1.
104	PARITYN			
111	REFCLKP	I	LVPECL	**Reference Clock Input (155 MHz).** This clock is optional. If applying the REFCLKP/N, set the REFCLKP/N to one of the following frequencies: ■ 155.52 MHz if using the TRCV012G5, or the TRCV012G7 at the 0C-48/STM-16 rate of 2.48832 GHz. ■ 166.62 MHz if using the TRCV012G7 at the RS FEC 0C-48/STM-16 rate of 2.66606 GHz.
110	REFCLKN			
113	REFSELN	I^u	CMOS	**Reference Select to PLL.** Selects LAINP/N or DATAP/N, or REFCLKP/N as the input to the CDR PLL. 0 = select REFCLKP/N 1 or no connection = select LAINP/N or DATAP/N

* Differential pins are indicated by the P and N suffixes. For nondifferential pins, N at the end of the symbol name designates active-low.

† I = input, O = output. I^u = an internal pull-up resistor on this pin, I^d = an internal pull-down resistor on this pin, I^t = an internal termination resistance of 50 Ω on this pin.

Pin Information (continued)

Table 3. Pin Descriptions—Global Signal

Pin	Symbol*	Type†	Level	Name/Description
116	RESETN	I^u	CMOS	**Reset (Active-Low).** Resets all synchronous logic. During a reset, the true data outputs are in the low state and the barred data outputs are in the high state. 0 = reset 1 or no connection = normal operation

* Differential pins are indicated by the P and N suffixes. For nondifferential pins, N at the end of the symbol name designates active-low.

† I = input, O = output. I^u = an internal pull-up resistor on this pin, I^d = an internal pull-down resistor on this pin, I^t = an internal termination resistance of 50 Ω on this pin.

Table 4. Pin Descriptions—Power and No-Connect Signals

Note: V$_{CCA}$, V$_{CCLA}$, and V$_{CCD}$ have the same dc value, which is represented as V$_{CC}$ unless otherwise specified. However, high-frequency filtering is suggested between the individual supplies.

Pin	Symbol*	Type†	Level	Name/Description
9, 10, 22, 23	V$_{CCA}$	I	Power	**Analog Power Supply (3.3 V).**
24, 27, 35	V$_{CCLA}$	I	Power	**Limiting Amplifier Power Supply (3.3 V).**
8, 42, 45, 48, 56, 59, 71, 76, 81, 89, 94, 99, 106, 109, 112, 127	V$_{CCD}$	I	Power	**Digital Power Supply (3.3 V).**
13, 15, 20, 21, 29, 31, 33, 1, 7, 36, 38, 39, 49, 52, 55, 64—68, 86, 102, 103, 128	GND	I	Ground	**Ground.**
11, 12, 14, 126	NC			**No Connection.** These pins must be left open.

* Differential pins are indicated by the P and N suffixes. For nondifferential pins, N at the end of the symbol name designates active-low.

† I = input, O = output. I^u = an internal pull-up resistor on this pin, I^d = an internal pull-down resistor on this pin, I^t = an internal termination resistance of 50 Ω on this pin.

Functional Overview

The Lucent Technologies Microelectronics Group TRCV012G5 operates at the OC-48/STM-16 data rate of 2.5 Gbits/s.* The TRCV012G7 device operates at either 2.5 Gbits/s or the RS FEC OC-48/STM-16 data rate of 2.7 Gbits/s. The device performs the data detection, clock recovery, and 1:16 demultiplexing operations required to support 2.5 Gbits/s applications compliant with *Telcordia Technologies* and ITU standards. A differential limiting amplifier with an adjustable threshold amplifies the 2.5 Gbits/s serial data waveform from an off-chip transimped-ance amplifier (TIA). Alternatively, a CML logic level input can be selected as the data source. A PLL recovers the clock which is used to retime the data. The decision sampling phase can be adjusted for optimal system perfor-mance. The 2.5 Gbits/s serial data and the 2.5 GHz recovered clock signal are available at CML outputs, or alter-natively, they can be disabled or the data can be muted. A 1:16 data demultiplexer performs the serial-to-parallel conversion and generates 16 parallel outputs at a 155 Mbits/s rate as well as a parity indicator. The parallel output data is aligned to a 155 MHz clock derived from the 2.5 GHz recovered clock. Loss of analog signal (LOSA) and loss of digital transitions (LOSD) are indicated. A 155 MHz reference clock may optionally be applied to serve as a frequency reference when data timing is lost.

Limiting Amplifier

Limiting Amplifier Operation

The limiting amplifier receives the input serial 2.5 Gbits/s data waveform from a transimpedance amplifier interface. The limiting amplifier inputs are internally terminated with 50 Ω resistors to ensure high input return loss perfor-mance. The signal is amplified with a small signal gain of approximately 30 dB to a saturation level of approxi-mately 800 mVp-p in order to provide a digital waveform to the clock and data recovery PLL. Full limiting is guaranteed for inputs of 15 mVp-p or greater on each input rail (30 mVp-p differential). If the input signal level is below a user-configurable threshold for a sufficiently long period of time, the LOSA signal is asserted. (For more detail on the LOSA functions, see the Analog Loss of Signal (LOSAN, PRG_LOSA) section on page 16.)

A typical interface between the lightwave receiver and the limiting amplifier is shown in Figure 3.

Note: It is recommended to use a differential interface from the lightwave receiver device with ac coupling.

The slicing level can be adjusted by varying the voltage on the SLADJ pin within ±300 mV of $V_{CC}/2$. This feature can be used to improve BER performance in optical receivers and optical amplifier systems. The relationship between the external voltage and the slicing level is given in Table 9 on page 20. If the voltage at this pin is tied below 0.5 V, the external slice adjustment is disabled and only the internal offset cancellation feature is active. The user should connect the SLADJ pin to GND if the slice adjust feature is not needed. The limiting amplifier will per-form in accordance with the specifications shown in Table 9.
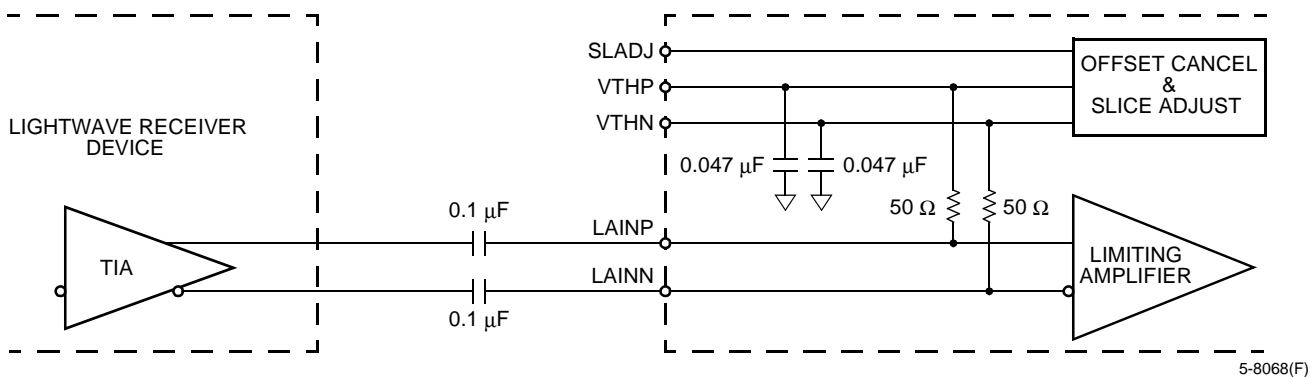

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Figure 3. Typical TIA to Limiting Amplifier Interface

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* The OC-48/STM-16 data rate of 2.48832 Gbits/s is typically approximated as 2.5 Gbits/s in this document when referring to the application rate. The RS FEC OC-48/STM-16 data rate is 2.66606 Gbits/s and is approximated as 2.7 Gbits/s in this document. Similarly, the OC-3/STM-1 data rate of 155.52 Mbits/s is typically approximated as 155 Mbits/s, and the RS FEC OC-3/STM-1 data rate of 166.62 Mbits/s is approximated as 166 Mbits/s. The exact frequencies are used only when necessary for clarity.

Clock and Data Recovery (CDR)

Clock Recovery Operation

The CDR circuit uses a PLL to extract the clock and retime the 2.5 Gbits/s data. The 2.5 Gbits/s data and the 2.5 GHz recovered clock are available as outputs, as well as a 155 MHz clock derived from the recovered clock.
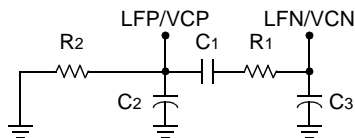
Clock Recovery PLL Loop Filter

A typical loop filter that meets the OC-48 jitter transfer template is shown in Figure 4. Connect the filter components and also connect LFP to VCP and connect LFN to VCN. The component values can be varied to adjust the loop dynamic response (see Table 5).

Table 5. Clock Recovery Loop Filter Component Values

Components	Values for 2 MHz Loop Bandwidth
C1*	0.47 μF ± 10%
C2, C3	10 pF ± 20%
R1	82.5 Ω ± 5%
R2	100 kΩ ± 5%

* Capacitor C1 should be either ceramic or nonpolar.

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Figure 4. Clock Recovery PLL Loop Filter Components

CDR Acquisition Time

The limiting amplifier plus CDR will acquire phase/frequency lock within 10 ms after powerup and a valid SONET signal or a $2^{23} - 1$ PRBS data signal is applied.

CDR Generated Jitter

The limiting amplifier plus CDR's generated jitter performance meets the requirements shown in Table 6. These specifications apply to the jitter generated at the 2.5 Gbits/s recovered clock pins (CK2G5P/N) when the following occur: no jitter is present on the input, the limiting amplifier's input signal is within the valid level range given in Table 9 on page 20, and the data sequence is a valid OC-48 SONET/SDH signal.

Table 6. Clock and Data Recovery Generated Jitter Specifications

Parameter	Typical	Max (Device)*	Unit
Generated Jitter (p-p): Measured with 12 kHz to 20 MHz Bandpass Filter	0.06	0.10	UIp-p
Generated Jitter (rms): Measured with 12 kHz to 20 MHz Bandpass Filter	0.008	0.01	UIrms

* This denotes the device specification for system SONET/SDH compliance when the loop filter in Table 5 and Figure 4 is used.

Clock and Data Recovery (CDR) (continued)
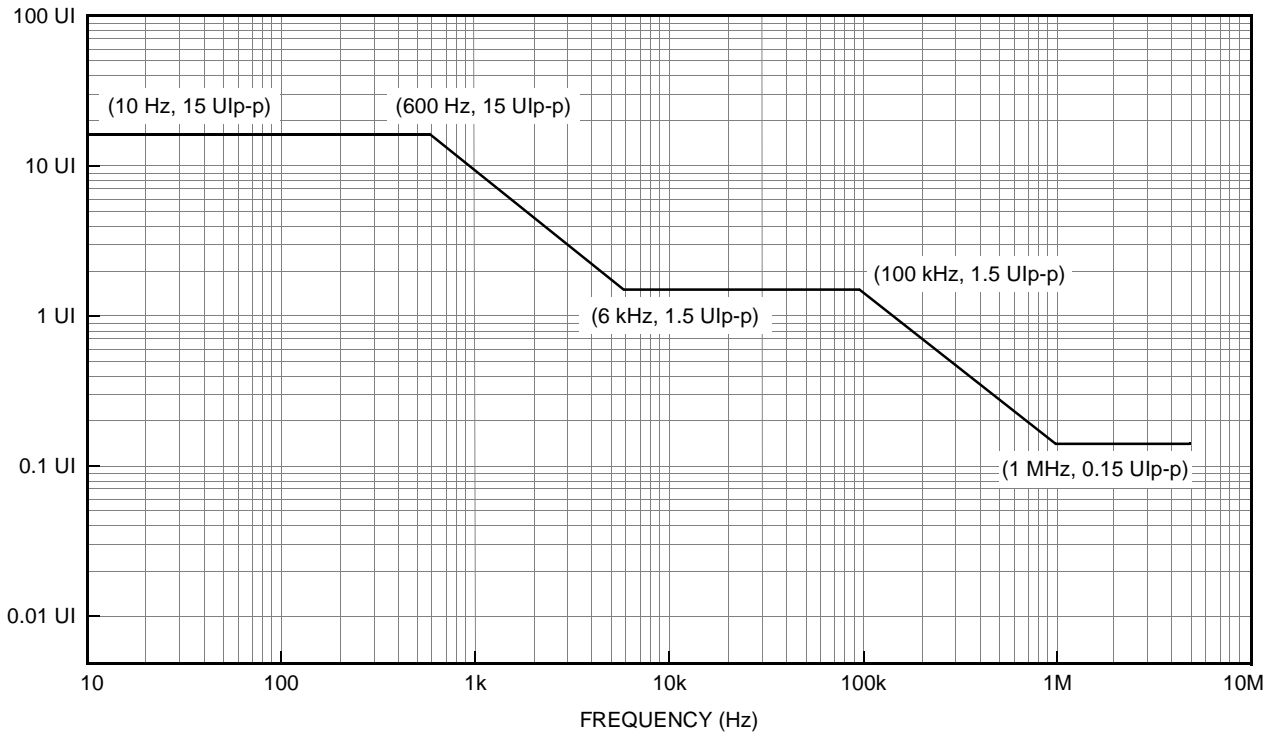
CDR Input Jitter Tolerance

The limiting amplifier plus CDR's jitter tolerance performance meets the requirement shown in Figure 5 on page 13 when the limiting amplifier's input signal is within the valid level range given in Table 9 on page 20, the loop filter in Figure 4 is used, and the data sequence is a valid OC-48 SONET/SDH signal.

CDR Jitter Transfer

Using the loop filter in Figure 4, the CDR's jitter transfer performance meets the requirement shown in Figure 6 when the input jitter magnitude is within the jitter tolerance requirements given in Figure 5 and the data sequence is a valid OC-48 SONET/SDH signal. This specification applies to the jitter transferred from the limiting amplifier's input to the 2.5 Gbits/s recovered clock pins (CK2G5P/N).
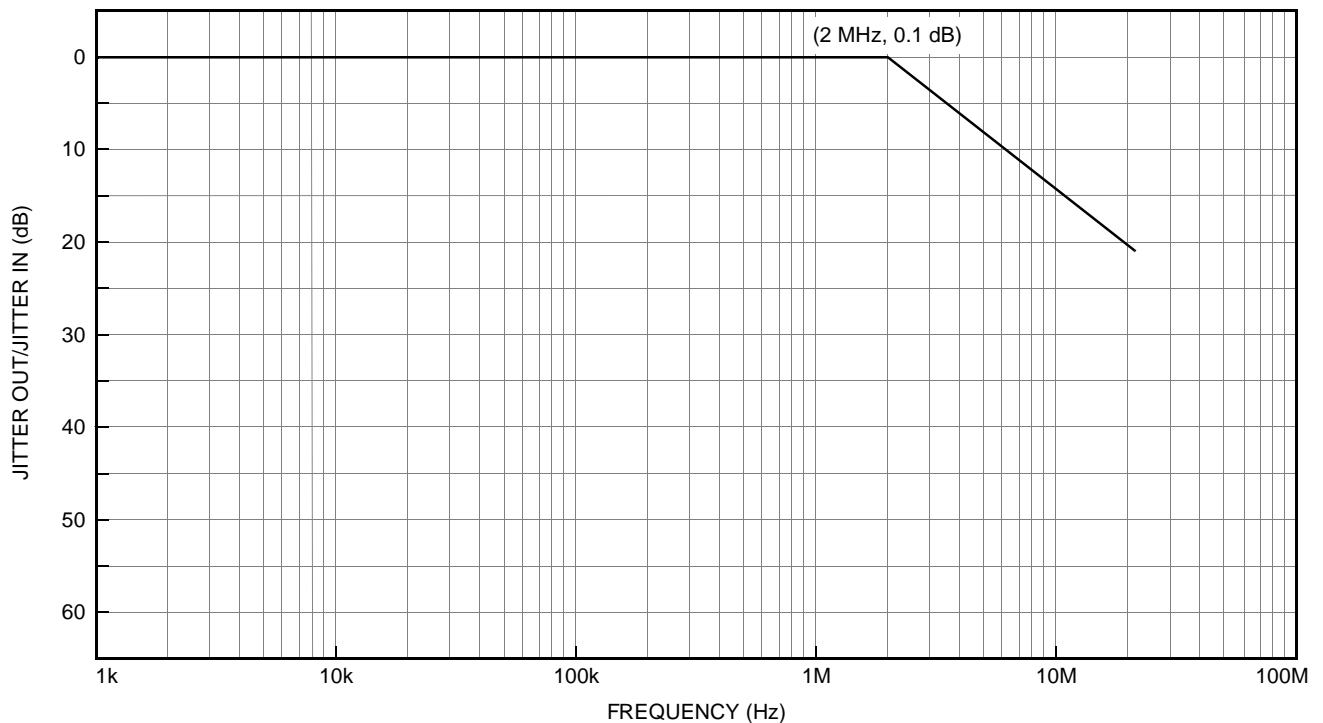
Clock and Data Recovery (CDR) (continued)

Clock Recovery Jitter Tolerance and Jitter Transfer Specifications

Figure 5. Receiver Jitter Tolerance

Figure 6. Receiver Jitter Transfer

Clock and Data Recovery (CDR) (continued)

Data Path Configuration Option (ENDATAN)

Either the limiting amplifier (LAINP/N) or a CML logic level input (DATAP/N) can be selected as the source of the 2.5 Gbits/s data signal. The DATAP/N input can be used if the limiting amplifier is not needed, or it can be used as a system loopback path when the limiting amplifier is the normal data path. If the limiting amplifier is not used in normal operation, the LAINP/N pins should be grounded through a series ac coupling of 0.1 μF.

High-Speed Serial Clock and Data Output Enables (ENCK2G5N, END2G5N)

Separate output enables are provided for the 2.5 GHz recovered clock output (CK2G5P/N) and the 2.5 Gbits/s data output (D2G5P/N). These enables are active-low CMOS inputs with internal pull-up resistors. A ground or logic low applied to the pin enables the corresponding output. When disabled, the pins should be either left floating, or be connected to a load which returns to Vcc. The high-speed serial clock and data outputs must not be connected directly to ground when they are disabled.

High-Speed Serial Data Output Mute (MUTE2G5N)

The 2.5 Gbits/s data output (D2G5P/N) may be forced to a logic-low state using MUTE2G5N. This may be desirable if the quality of the input data is suspect, as may be the case under LOSA or LOSD conditions. MUTE2G5N is an active-low CMOS input.

Data and CDR Configuration Options (REFSELN, INLOSN, MUTEDMXN)

A 155 MHz clock (REFCLKP/N) may optionally be provided as a frequency reference to the clock recovery PLL in order to control the recovered clock frequency when data timing is lost, as may be the case under LOSA or LOSD conditions. If REFCLKP/N is provided, REFSELN can be used to select REFCLKP/N as the frequency reference to the clock recovery PLL.

The INLOSN pin will force the VCO to decrease to its minimum frequency. This will prevent the VCO frequency from drifting to a high value during invalid signal conditions. INLOSN may be used to limit the recovered clock frequency in systems that do not provide a REFCLKP/N signal.

The MUTEDMXN pin will force logic-low data into the demultiplexer, and therefore, keep all demultiplexer outputs in the logic-low state. MUTEDMXN will not affect the operation of the CDR circuits. This may be desirable if the quality of the input data is suspect as may be the case under LOSA or LOSD conditions.

The user may utilize the REFSELN, INLOSN, and MUTEDMXN pins in any combination to achieve the desired response under LOS conditions.

Decision Circuit—Adjustable Sampling Time (ASTREF, AST[4:0])

The adjustable sampling time (AST) feature allows a deliberate time offset to be introduced for the data recovery sampling instant relative to the recovered clock. The sampling instant is normally set by the clock recovery phase-locked loop (PLL) to be midway between the mean values of adjacent NRZ data polarity transitions, which provides an ideal setup and hold time margin of one half the data period. By setting the AST[4:0] control bits, the user may shift the instant at which the PLL's recovered clock samples the receive data eye. The AST[4] bit acts as a polarity setting, AST[3] represents the most significant magnitude bit, and AST[0] represents the least significant magnitude bit. Since this results in two decoded zero time offset states, AST[4:0] = 00000 is used to disable the sampling offset feature entirely and will result in traditionally defined midpoint sampling, whereas AST[4:0] = 10000 will also result in midpoint sampling by using the AST feature in its zero time offset condition. With AST[4] set to a logic high, increasing the AST[3:0] hexadecimal code causes the sampling point to monotonically advance in time; with AST[4] set to a logic low, the sample time is delayed more as AST[3:0] increases. The ASTREF pin should be tied to the positive power supply through a low-capacitance 1%, 2.1 kΩ resistor. This provides a stable reference resistor to the AST circuitry.

The AST control bit configurations and corresponding offset times are shown in Table 7.

Table 7. Adjustable Sampling Time (AST) Control Code

Note: When operating the TRCV012G7 at the FEC rate, the 6.25 ps
step should be scaled down by 7%.

| AST[4:0]	Time Offset (ps)	AST[4:0]	Time Offset (ps)
01111	−93.75	10000	0.00
01110	−87.50	10001	6.25
01101	−81.25	10010	12.50
01100	−75.00	10011	18.75
01011	−68.75	10100	25.00
01010	−62.50	10101	31.25
01001	−56.25	10110	37.50
01000	−50.00	10111	43.75
00111	−43.75	11000	50.00
00110	−37.50	11001	56.25
00101	−31.25	11010	62.50
00100	−25.00	11011	68.75
00011	−18.75	11100	75.00
00010	−12.50	11101	81.25
00001	−6.25	11110	87.50
00000	0.00	11111	93.75

Loss of Signal Detection

The loss of signal circuits are used to detect the conditions of low input signal level or no data transitions at the input. The LOSDN and LOSAN signals can be processed and/or filtered to meet various system-dependent requirements on declaring loss of signal.

Digital Loss of Signal (LOSDN)

The LOSDN signal alarm is set when no transitions appear in the data path for more than 2.3 μs. The LOSDN signal will become active before 100 μs of no transitions has occurred. When ac coupling the 2.5 Gbits/s data to the high gain limiting amplifier, in the presence of no significant amplitude data transitions, noise at the limiting amplifier's input may be amplified and appear to be a data transition. This may change the state of LOSDN.

Analog Loss of Signal (LOSAN, PRG_LOSA)

Low signal levels are detected by the limiting amplifier with an optional user-programmable analog loss of signal (LOSA) threshold. As shown in Figure 7, applying a voltage to the PRG_LOSA pin will adjust the LOSA trip point. When the voltage on PRG_LOSA is 0 V, LOSAN will never be active even if the level at the limiting amplifier input is zero. When the voltage on PRG_LOSA is greater than approximately 1 V and less than 2 V, LOSAN will always be active regardless of the signal level at the limiting amplifier input. If the voltage of the PRG_LOSA pin exceeds 2 V, the threshold defaults to approximately 12 mVp-p differential. This voltage can be adjusted while monitoring the BER of the system, and is typically set to activate LOSAN for input levels corresponding to a BER of just above 10^{-3}. LOSAN will not be asserted unless the alarm condition exists for at least 2.3 μs. The LOSAN pin will be deasserted when the input level becomes greater than the LOSA threshold by an amount corresponding to 1 dB (typical) optical power input. The input resistance of the PRG_LOSA pin is typically 50 kΩ, so a resistor voltage divider between VCC and ground may be used to set the PRG_LOSA level if the VCC tolerance and variability is adequate.
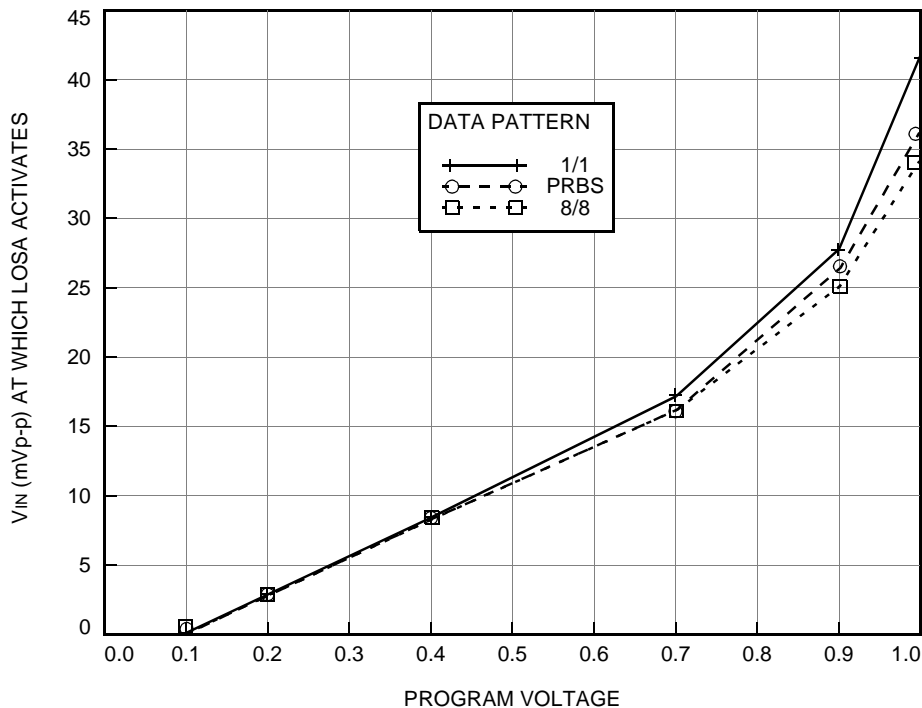

5-8070(F)r.2

Figure 7. Typical LOSA Threshold vs. PRG_LOSA Voltage vs. Data Pattern

Demultiplexer Operation

The serial 2.5 Gbits/s data is clocked into a 1:16 demultiplexer by the recovered 2.5 GHz clock. The demultiplexed parallel data is retimed with a 155 MHz clock that is derived from the recovered clock. The relationship between the serial input data and the parallel D[15:0] bits is given in Figure 8. D15 is the bit that was received first in time in the serial input data stream.
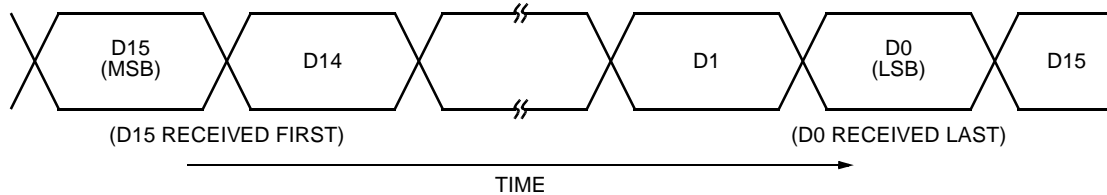
5-8063(F).a

Figure 8. Serial Input to Parallel Output Data Relationship

Parity Generation (PARITYP/N)

The parity pin (PARITYP/N) is a logic 0 when the number of 1s in the 16-bit output register is an even number, and the parity pin is a logic 1 when the number of 1s in the output register is an odd number.

Demultiplexer Powerdown (PDDMXN)

The entire demultiplexer and parity generator functionality can be powered down for systems requiring only the 2.5 GHz clock and data outputs. Setting PDDMXN = 0 powers down the demultiplexer and parity generation functions as well as the CK155P/N output clock signal. When PDDMXN = 0, the D[15:0] and PARITYP/N pins should be left unconnected.

Demultiplexer Data Mute (MUTEDMXN)

Setting the MUTEDMXN = 0 mutes the data going into the demultiplexer and forces all zeros to appear at the parallel outputs (D[15:0]).

CK155P/N Low-Speed Output Mute (MUTE155N)

The 155 MHz low-speed clock output (CK155P, CK155N) can be forced to logic low by setting MUTE155N, which is an active-low CMOS input with an internal pull-up resistor. A ground or logic low applied to MUTE155N mutes the CK155P/N output.

CML Output Structure (Used on Pins D2G5P/N, CK2G5P/N)

The CML architecture is essentially a current-steering mechanism combined with an amplifier. This makes the output swing of the signal a function of the termination resistor and the programmable output current. The user should connect external termination resistors from the CML output pins to Vcc. The on-chip, 100 Ω pull-up resistors provide a dc path when using an ac-coupled load.

The voltage swing of a CML signal is typically 400 mV, half that of ECL/PECL. The lower pulse amplitude reduces noise transients, crosstalk, and EMI. It also uses half the amount of current through the termination resistors. The schematic of a typical CML output structure is shown in Figure 9.
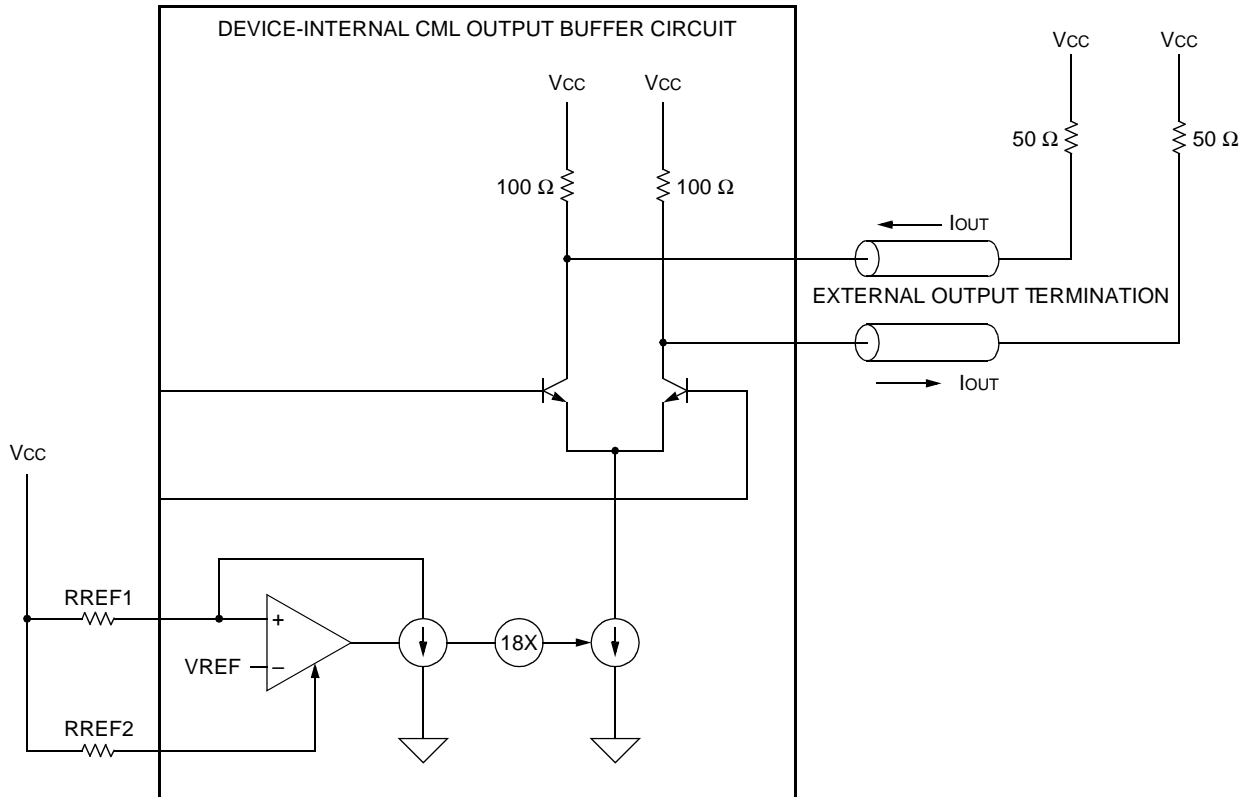
5-8065(F)r.2

Figure 9. Typical CML Output Structure

Choosing the Value of the External CML Reference Resistors (RREF1, RREF2)

The flexibility of the CML interface permits certain parameters to be customized for a particular application. The RREF1 resistor controls the CML output driver current source. Adjusting this tail current and termination resistors will allow signal amplitude control (see the CML output specifications for limitations, page 22 and page 24) and flexibility in termination schemes.

With RREF2 set to 1.5 kΩ, the equation for the CML output current is the following:

$$Iout = (18)*(1.21)/RREF1$$

The CML outputs have on-chip 100 Ω load resistors to Vcc in order to accommodate capacitive ac coupling. With a 50 Ω 1% load, the effective load resistance will be 33.33 Ω ± 6%. For a 400 mV voltage swing into the 50 Ω load, set RREF1 to 1.8 kΩ. For a 600 mV voltage swing, set RREF1 to 1.2 kΩ. In both cases, RREF2 remains fixed at a value of 1.5 kΩ.

Absolute Maximum Ratings

Stresses in excess of the absolute maximum ratings can cause permanent damage to the device. These are absolute stress ratings only. Functional operation of the device is not implied at these or any other conditions in excess of those given in the operational sections of the data sheet. Exposure to absolute maximum ratings for extended periods can adversely affect device reliability.

Parameter	Min	Max	Unit
Power Supply Voltage (V_{CC})	—	4.0	V
Storage Temperature	−40	125	°C
Pin Voltage	GND − 0.5	V_{CC} + 0.5	V

Handling Precautions

Although protection circuitry has been designed into this device, proper precautions should be taken to avoid exposure to electrostatic discharge (ESD) during handling and mounting. Lucent employs a human-body model (HBM) and charged-device model (CDM) for ESD-susceptibility testing and protection design evaluation. ESD voltage thresholds are dependent on the circuit parameters used in the defined model. No industrywide standard has been adopted for the CDM. However, a standard HBM (resistance = 1500 Ω, capacitance = 100 pF) is widely used and, therefore, can be used for comparison purposes:

Device	Voltage
TRCV012G5	≥200 V
TRCV012G7	≥200 V

Operating Conditions

Table 8. Recommended Operating Conditions

Parameter	Symbol	Min	Typ	Max	Unit
Power Supply (dc voltage)	—	3.135	3.3	3.465	V
Ground	—	—	—	—	V
Input Voltage: Low High	V_{IL} V_{IH}	(See Table 11, Table 13, Table 15.)	(See Table 11, Table 13, Table 15.)	(See Table 11, Table 13, Table 15.)	V V
Temperature: Ambient Junction	T_A —	−40 0	— —	85 125	°C °C
Power Dissipation: MBIC 025 BiCMOS MBIC 025 SiGe BiCMOS	P_D P_D	— —	2.5 1.45	3.43 1.73	W W

Electrical Characteristics

Limiting Amplifier Specifications

Table 9. Limiting Amplifier Characteristics

Parameter	Min	Typical	Max	Unit
Data Input Level for Full Amplifier Limiting (differential input)	30	—	1200	mVp-p
Small-signal Gain	26	30	32	dB
Small-signal Bandwidth	3	—	—	GHz
Input Referred Wideband Noise (dc—2.5 GHz)	—	—	170	μVrms
Input Return Loss (LAINP/LAINN pins): 100 MHz—2 GHz 2 GHz—3 GHz	— —	— —	−20 −15	dB dB
Input Slice Level Adjustment	—	$0.01*(SLADJ - V_{CC}/2)$	—	V
SLADJ Input Range	$V_{CC}/2 - 0.3$	—	$V_{CC}/2 + 0.3$	V
Slice Feature Disable Voltage (SLADJ)	—	—	0.5	V

Optional Reference Frequency (REFCLKP/N) Specifications

The CDR operates without any reference clock. However, a reference clock input is available should the user want to maintain the CDR frequency lock without any data input.

■ When using the TRCV012G5 device, a 155.52 MHz differential LVPECL clock can be applied to the REFCLKP/N input.

■ When using the TRCV012G7 device at the OC-48/STM-16 rate, a 155.52 MHz differential LVPECL clock can be applied to the REFCLKP/N input.

■ When using the TRCV012G7 device at the RS FEC OC-48/STM-16 rate, a 166.62 MHz differential LVPECL clock can be applied to the REFCLKP/N input.

Table 10 provides the characteristics of the REFCLKP/N input.

Table 10. Reference Frequency Characteristics

Parameter	Min	Typ	Max	Unit
Reference Frequency (REFCLKP/N)	—	155.52	—	MHz
	—	166.62	—	MHz
Reference Frequency Tolerance*	−20	—	20	ppm
Duty Cycle	40	—	60	%
Temperature†	−40	—	85	°C
Supply Voltage†	3.10	—	3.60	V

* Includes effects of power supply variation, temperature, electrical loading, and aging. The ±20 ppm tolerance is required to meet SONET/SDH requirements if the reference frequency is used for system clocking when timing recovery is lost.

† Specified range is to be compatible with environmental specification of TRCV012G5 or TRCV012G7. Applications requiring a reduced temperature range may specify the reference frequency oscillator accordingly.

Electrical Characteristics (continued)

LVPECL, CMOS, CML Input and Output Pins

Notes:
1. For Table 11 through Table 18, V_{CC} = 3.3 V ± 5%, T_A = –40 °C to +85 °C; these tables apply to both MBIC 025 BiCMOS and MBIC 025 SiGe BiCMOS technologies.

2. For more information on interpreting CML specifications, see the CML Output Structure (Used on Pins D2G5P/N, CK2G5P/N) section on page 18.

Table 11. LVPECL Input Pin Characteristics

Applicable Pins	Symbol	Parameter	Conditions	Min	Typ	Max	Unit
REFCLKP/N	V_{IH}	Input Voltage High	Referred to V_{CC}	–1165	—	–880	mV
	V_{IL}	Input Voltage Low	Referred to V_{CC}	–1810	—	–1475	mV
	I_{IH}	Input Current High Leakage	$V_{IN} = V_{IH}$ (max)	—	—	20	µA
	I_{IL}	Input Current Low Leakage	$V_{IN} = V_{IL}$ (min)	5	—	—	µA

Table 12. LVPECL Output Pin Characteristics

Applicable Pins	Symbol	Parameter	Conditions	Min	Typ	Max	Unit
D[15:0]P/N, PARITYP/N, CK155P/N	V_{OH}	Output Voltage High	Load = 50 Ω connected to V_{CC} – 2.0 V	V_{CC} – 1.31	V_{CC} – 1.20	V_{CC} – 0.90	V
	V_{OL}	Output Voltage Low	Load = 50 Ω connected to V_{CC} – 2.0 V	V_{CC} – 1.95	V_{CC} – 1.88	V_{CC} – 1.80	V

Table 13. CMOS Input Pin Characteristics

Applicable Pins	Symbol	Parameter	Conditions	Min	Max	Unit
END2G5N, ENCK2G5N, RESETN, ENDATAN, ENDATCKN, REFSELN, MUTEDMXN, PDDMXN, MUTE155N, MUTE2G5N	V_{IH}	Input Voltage High	—	V_{CC} – 1.0	V_{CC}	V
	V_{IL}	Input Voltage Low	—	GND	1.0	V
	I_{IH}	Input Current High Leakage	$V_{IN} = V_{CC}$	—	10	µA
	I_{IL}	Input Current Low Leakage	$V_{IN} = GND$	–225	—	µA
AST[4:0]	I_{IH}	Input Current High Leakage	$V_{IN} = V_{CC}$	—	225	µA
	I_{IL}	Input Current Low Leakage	$V_{IN} = GND$	–10	—	µA

Table 14. Open Drain Output Pin Characteristics

Applicable Pins	Symbol	Parameter	Conditions	Min	Max	Unit
LOSAN, LOSDN	V_{OH}	Output Voltage High	$R_L \geq 5$ kΩ	V_{CC} – 0.5	V_{CC}	V
	V_{OL}	Output Voltage Low	$R_L \geq 5$ kΩ	GND	0.5	V
	C_I	Output Load Capacitance	—	—	30	pF

Electrical Characteristics (continued)

LVPECL, CMOS, CML Input and Output Pins (continued)

Table 15. CML Input Pin dc Characteristics

Applicable Pins	Symbol	Parameter	Conditions	Min	Typ	Max	Unit
DATAP/N, DATCKP/N	V_{IL}	Input Voltage Low	—	—	$V_{CC} - 0.4$	—	V
	V_{IH}	Input Voltage High		—	V_{CC}	—	V

Table 16. CML Output Pin dc Characteristics

Applicable Pins	Symbol	Parameter	Conditions	Min*	Typ†	Max‡	Unit
D2G5P/N, CK2G5P/N	V_{OL}	Output Voltage Low	RREF2 = 1.5 kΩ RL = 50 Ω All signals differential	$V_{CC} - 1.2$	$V_{CC} - 0.4$	—	V
	V_{OH}	Output Voltage High		—	V_{CC}	$V_{CC} + 0.3$	V
	I_{OL}	Output Current Low		3.6	12	18	mA
	I_{OH}	Output Current High		—	0	1	μA

* Applies when RREF1 = 1 kΩ.
† Applies when RREF1 = 1.8 kΩ.
‡ Applies when RREF1 = 6 kΩ.

Timing Characteristics

Output Timing

The timing relationships between the 155 MHz or 166 MHz output clock (CK155P/N) and the output demultiplexer data (D[15:0]P/N) and the output parity (PARITYP/N) are shown in Figure 10.
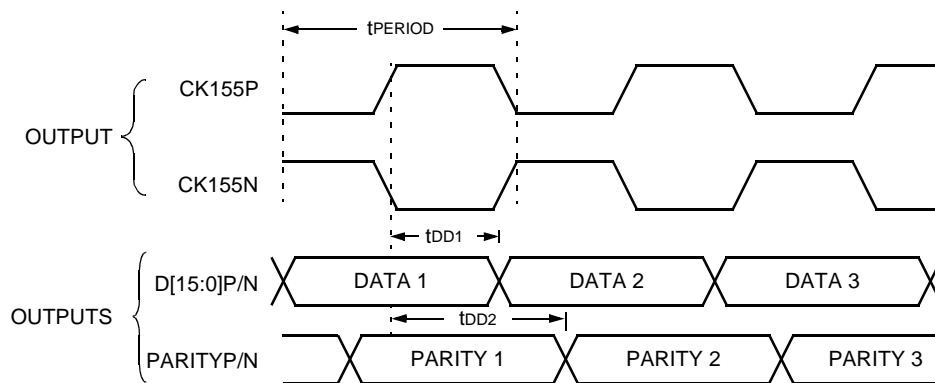
5-7726(F).fr.4

Figure 10. Transmit Timing Waveform with 155 MHz or 166 MHz Clock

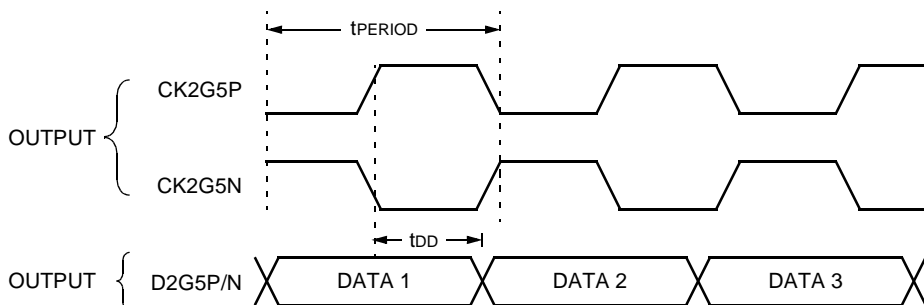The 155 MHz or 166 MHz output clock and data signals from Figure 10 are characterized in Table 17.

Table 17. LVPECL Output Pin ac Timing Characteristics

Applicable Pins	Symbol	Parameter	Conditions	Min	Typ	Max	Unit
CK155P/N	—	Duty Cycle	All signals differential	48	50	52	%
	t_{PERIOD}	155.52 MHz Clock Period		—	6.43	—	ns
		166.62 MHz Clock Period		—	6.00	—	ns
D[15:0]P/N, PARITYP/N, CK155P/N	t_{DD1}	Time Delay from Clock Edge to D[15:0]P/N Edge		2.9	3.2	3.9	ns
	t_{DD2}	Time Delay from Clock Edge to PARITYP/N Edge		3.3	4.0	4.7	ns
	t_{RISE}, t_{FALL}	Rise, Fall Times: 20%—80%		200	500	800	ps
	t_{SKEW}	Transition Skew Rise to Fall		−100	0	100	ps

Timing Characteristics (continued)

Output Timing (continued)

The timing relationship between the 2.5 GHz or 2.7 GHz output clock (CK2G5P/N) and the 2.5 Gbits/s or 2.7 Gbits/s output data (D2G5P/N) is shown in Figure 11.

5-7726(F).er.4

Figure 11. Transmit Timing Waveform with 2.5 GHz or 2.7 GHz Clock

The 2.5 GHz or 2.7 GHz output clock and data signals from Figure 11 are characterized in Table 18.

Table 18. CML Output Pin ac Timing Characteristics

Applicable Pins	Symbol	Parameter	Conditions	Min	Typ	Max	Unit
CK2G5P/N	—	Duty Cycle	RREF1 = 1.8 kΩ RREF2 = 1.5 kΩ R_L = 50 Ω All signals differential	40	50	60	%
	t_{PERIOD}	2.48832 GHz Clock Period		—	402	—	ps
		2.66606 GHz Clock Period		—	375	—	ps
D2G5P/N, CK2G5P/N	t_{DD}	Time Delay from Clock Edge to D2G5P/N Edge		151	201	251	ps
	t_{RISE}, t_{FALL}	Rise, Fall Times: 20%—80%		50	80	120	ps
	t_{SKEW}	Transition Skew Rise to Fall		−10	0	10	ps

Outline Diagram

128-Pin QFP

Dimensions are in millimeters.
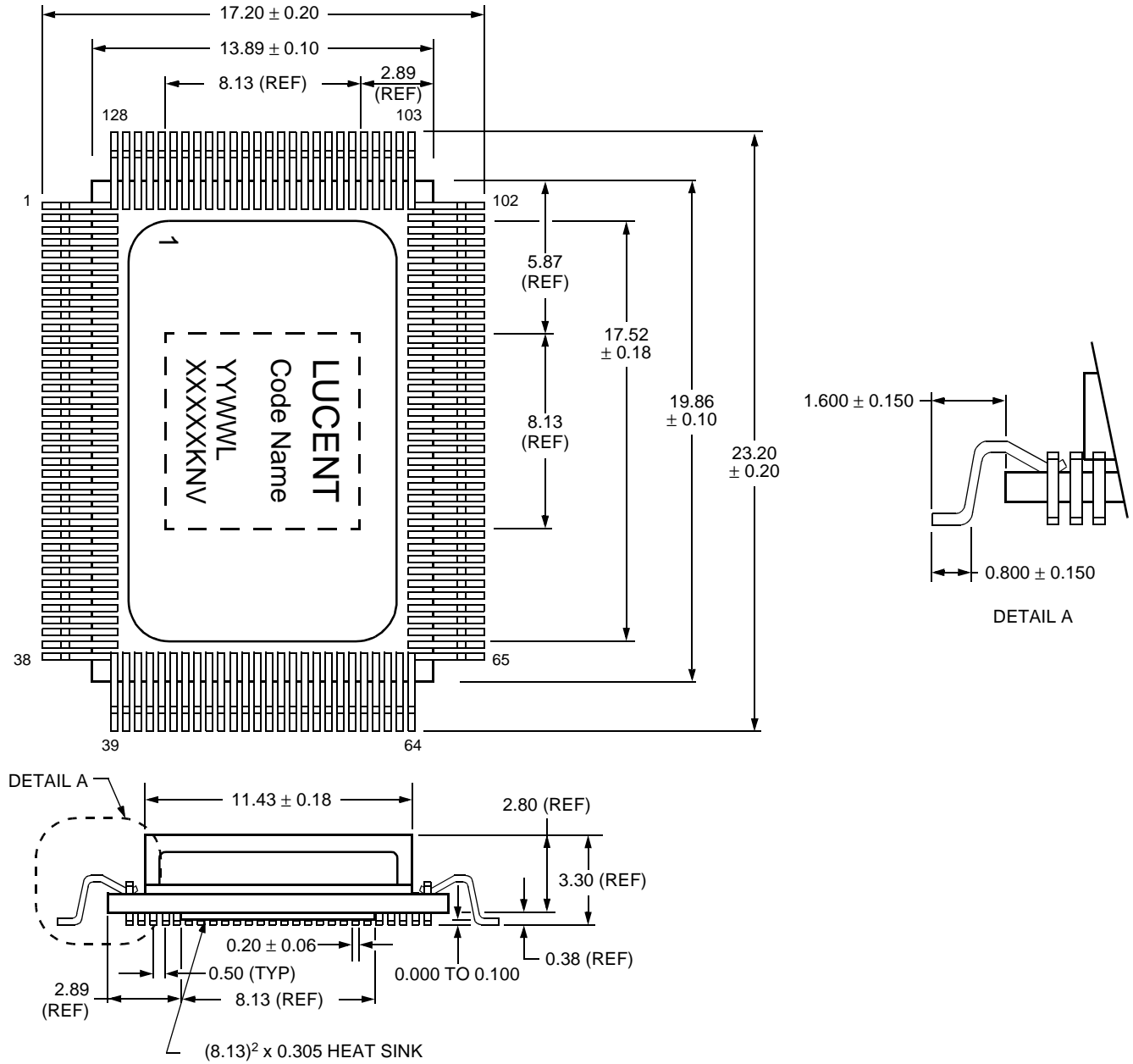
5-8416(F)r.2

Outline Diagram (continued)

Board Installation Recommendations
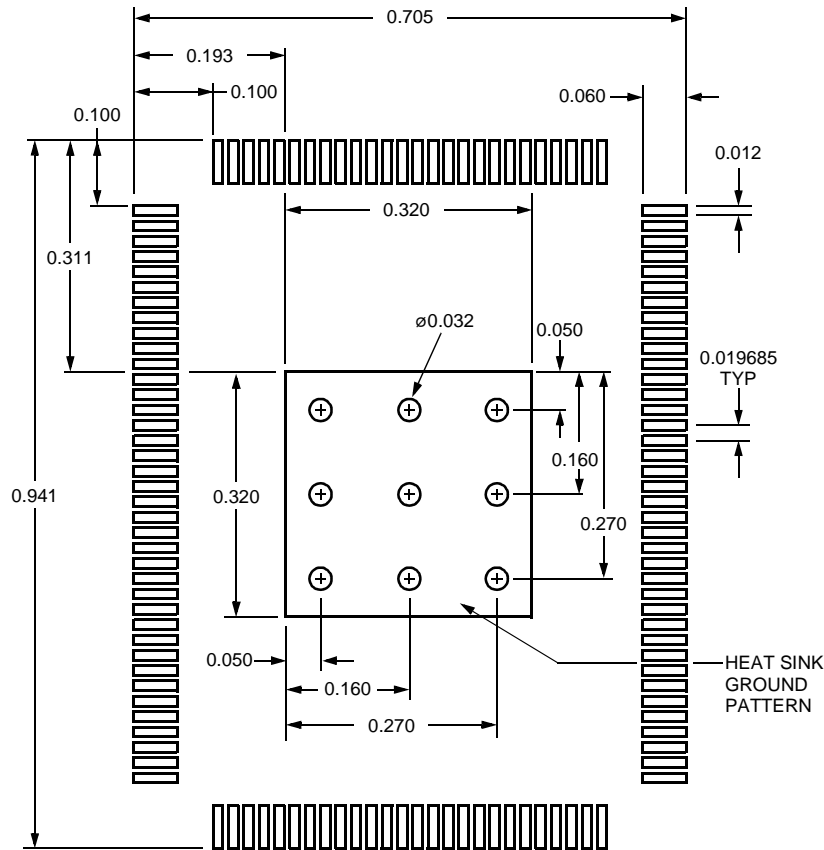
5-9862 (F)r.1

Figure 12. Heat Sink Ground Pattern

Thermal Considerations (MBIC 025 BiCMOS and MBIC 025 SiGe BiCMOS)

The TRCV012G5 and TRCV012G7 devices use a square heat sink on the bottom of the package for heat dissipation. This heat sink is planar with the lead surface which contacts the board. For optimum heat transfer, the heat sink should be soldered to the application board using the suggested footprint shown above. Depending on the application more heat sinking may be required.

Note: Certain precautions must be taken when using solder. For installation using a constant temperature solder, temperatures of under 300 °C may be employed for periods of time up to 5 seconds, maximum. For installation with a soldering iron (battery operated or non-switching only), the soldering tip temperature should not be greater than 300 °C and the soldering time for each lead must not exceed 5 seconds.

Table 19. Thermal Resistance

Parameter	Symbol	Conditions	Unit (°C/W)
Thermal resistance, junction to board	θ_{JB}	No air flow, device soldered to board	11.5
Thermal resistance, junction to ambient	θ_{JA}	100 lfpm, device soldered to board	18
		300 lfpm, device soldered to board	15.6
		500 lfpm, device soldered to board	14.6

Ordering Information

Device Code	Package	Temperature	Comcode (Ordering Number)
TRCV012G5:			
TRCV012G5 (BiCMOS)	128-pin QFP	–40 °C to +85 °C	108419953
TRCV012G53XE1 (SiGe BiCMOS)	128-pin QFP	–40 °C to +85 °C	108700675
TRCV012G7:			
TRCV012G7 (BiCMOS)	128-pin QFP	–40 °C to +85 °C	108560343
TRCV012G73XE1 (SiGe BiCMOS)	128-pin QFP	–40 °C to +85 °C	108700683
—	—	—	—

DS00-234HSPL Replaces DS00-154HSPL to Incorporate the Following Updates

1. Added a second technology, MBIC 025 SiGe BiCMOS, to the data sheet.
2. Page 8, REFCLKP/N pins, corrected definition.
3. Page 11, Table 5, updated C1, R1, and R2 values in Clock Recovery Loop Filter Component Values.
4. Page 19, Absolute Maximum Ratings, added maximum power supply value of 4.0 V.
5. Page 19, Handling Precautions, corrected ESD threshold value from TBD to ≥200 V.
6. Page 19, Table 8, corrected BiCMOS power dissipation from TBD to 3.43 W in Recommended Operating Conditions; added MBIC 025 SiGe BiCMOS power dissipation values.
7. Page 19, Table 8, added junction temperature in Recommended Operating Conditions.
8. Page 21, Table 12, corrected values in LVPECL Output Pin Characteristics.
9. Page 23, Table 17, updated minimum duty cycle from 40% to 48%, maximum duty cycle from 60% to 52%, and tDD1 minimum value from 2.5 ns to 2.9 ns in LVPECL Output Pin ac Timing Characteristics.
10. Page 26, added the section Board Installation Recommendations and Thermal Considerations (MBIC 025 BiCMOS and MBIC 025 SiGe BiCMOS).
11. Page 27, Ordering Information, added MBIC 025 SiGe BiCMOS comcodes.

m i c r o e l e c t r o n i c s   g r o u p

August 2000
DS00-234HSPL (Replaces DS00-154HSPL)

Lucent Technologies
Bell Labs Innovations